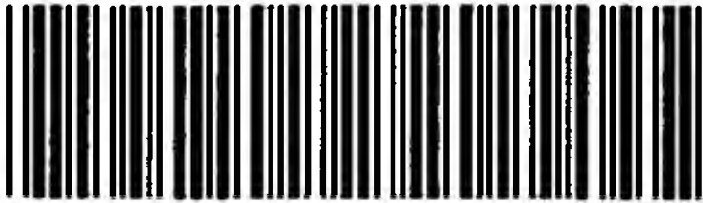


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/511,582	BOSMA, EPKE	
	Examiner	Art Unit	
	Son T. Nguyen	3643	

SEARCHED			
Class	Subclass	Date	Examiner
119	14.14-14.18	8/4/2006	STN
	14.08		
	14.01		
	14.02		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IPC foreign search: A01J 5/007	8/4/2006	STN
text search, see printout	8/2/2006	STN